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Test Conference, 1988. Proceedings. 'New Frontiers in Testing', International , 12-14 Sept. 1988

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Supercomputing '88. [Vol.1]. Proceedings. , 14-18 Nov. 1988

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Computer Design: VLSI in Computers and Processors, 1988. ICCD '88., Proceedings of the 1988 IEEE International Conference on , 3-5 Oct. 1988

Page(s): 458 -461

[\[Abstract\]](#) [\[PDF Full-Text \(288 KB\)\]](#) **IEEE CNF**

5 An iterative technique for calculating aliasing probability of linear feedback signature registers*Ivanov, A.; Agarwal, V.K.;*

Fault-Tolerant Computing, 1988. FTCS-18, Digest of Papers., Eighteenth International Symposium on , 27-30 June 1988

Page(s): 70 -75

[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) [IEEE CNF](#)**6 On the design of multiple-input shift-registers for signature analysis testing***Olivo, P.; Damiani, M.; Ricco, B.;*

Test Conference, 1989. Proceedings. 'Meeting the Tests of Time', International , 29-31 Aug. 1989

Page(s): 936

[\[Abstract\]](#) [\[PDF Full-Text \(80 KB\)\]](#) [IEEE CNF](#)**7 Experiments on aliasing in signature analysis registers***Xavier, D.; Aitken, R.C.; Ivanov, A.; Agarwal, V.K.;*

Test Conference, 1989. Proceedings. 'Meeting the Tests of Time', International , 29-31 Aug. 1989

Page(s): 344 -354

[\[Abstract\]](#) [\[PDF Full-Text \(516 KB\)\]](#) [IEEE CNF](#)**8 Aliasing in signature analysis testing with multiple-input shift-registers***Damiani, M.; Olivo, P.; Favalli, M.; Ercolani, S.; Ricco, B.;*

European Test Conference, 1989., Proceedings of the 1st , 12-14 April 1989

Page(s): 346 -353

[\[Abstract\]](#) [\[PDF Full-Text \(572 KB\)\]](#) [IEEE CNF](#)**9 Aliasing errors in multiple input signature analysis registers***Williams, T.W.; Daehn, W.;*

European Test Conference, 1989., Proceedings of the 1st , 12-14 April 1989

Page(s): 338 -345

[\[Abstract\]](#) [\[PDF Full-Text \(448 KB\)\]](#) [IEEE CNF](#)**10 Aliasing probability for multiple input signature analyzers with dependent inputs***Williams, T.W.; Daehn, W.;*

CompEuro '89., 'VLSI and Computer Peripherals. VLSI and Microelectronic Applications in Intelligent Peripherals and their Interconnection Networks', Proceedings. , 8-12 May 1989

Page(s): 5/120 -5/127

[\[Abstract\]](#) [\[PDF Full-Text \(360 KB\)\]](#) [IEEE CNF](#)

11 Signature analysers based on additive cellular automata

Das, A.K.; Saha, D.; Chowdhury, A.R.; Misra, S.; Chaudhuri, P.P.;
Fault-Tolerant Computing, 1990. FTCS-20. Digest of Papers., 20th International
Symposium , 26-28 June 1990
Page(s): 265 -272

[\[Abstract\]](#) [\[PDF Full-Text \(496 KB\)\]](#) [IEEE CNF](#)

12 Architectural support for register allocation in the presence of aliasing

Heggy, B.; Soffa, M.L.;
Supercomputing '90. Proceedings of , 12-16 Nov. 1990
Page(s): 730 -739

[\[Abstract\]](#) [\[PDF Full-Text \(832 KB\)\]](#) [IEEE CNF](#)

13 Estimating aliasing in CA and LFSR based signature registers

Miller, D.M.; Zhang, S.; Pries, W.; McLeod, R.D.;
Computer Design: VLSI in Computers and Processors, 1990. ICCD '90. Proceedings.,
1990 IEEE International Conference on , 17-19 Sept. 1990
Page(s): 157 -160

[\[Abstract\]](#) [\[PDF Full-Text \(300 KB\)\]](#) [IEEE CNF](#)

14 Design of signature circuits based on weight distributions of error-correcting codes

Iwasaki, K.; Yamaguchi, N.;
Test Conference, 1990. Proceedings., International , 10-14 Sept. 1990
Page(s): 779 -785

[\[Abstract\]](#) [\[PDF Full-Text \(532 KB\)\]](#) [IEEE CNF](#)

15 Reed-Solomon codes based novel signature analysis technique for VLSI random access memory testing

Rayapati, V.N.; Mukhedkar, D.;
Circuits and Systems, 1990., IEEE International Symposium on , 1-3 May 1990
Page(s): 2324 -2328 vol.3

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